

# Reliability of Technical Systems



## Main Topics

- Introduction, Key terms, framing the problem
- Reliability parameters: Failure Rate, Failure Probability, Availability, etc.
- **Some important reliability distributions**
- Component reliability
- Software reliability
- Fault Tolerance
- System reliability: Structure and State Modelling
- Dependent failure
- Human reliability
- Static and dynamic redundancy
- Advanced methods for systems modeling and simulation

## Most relevant distributions in Reliability Theorie:

- Continuous ones: **Exponential, Weibull, Normal, Log Normal, Uniform (Rectangular).**
- Discrete ones: **Poisson, Binomial (Bernoulli).**

| Number | Name | Distribution       |
|--------|------|--------------------|
| 1      |      | <b>Binomial</b>    |
| 2      |      | <b>Exponential</b> |
| 3      |      | <b>Log Normal</b>  |
| 4      |      | <b>Normal</b>      |
| 5      |      | <b>Poisson</b>     |
| 6      |      | <b>Uniform</b>     |
| 7      |      | <b>Weibull</b>     |

## Exponential distribution

The exponential distribution is the **only** continuous memoryless random distribution.

The exponential distribution is the most common and simplest distribution function to model the reliability of components.

The failure rate and the time to failure are reciprocal.

Application: To estimate the reliability of components/systems with **constant failure rate**.

## Exponentially Distributed Time to Failure

If the time to failure is exponential distributed with parameter  $\lambda$ , we obtain:

Density:  $f_L(t) = \lambda \cdot e^{-(\lambda \cdot t)}$

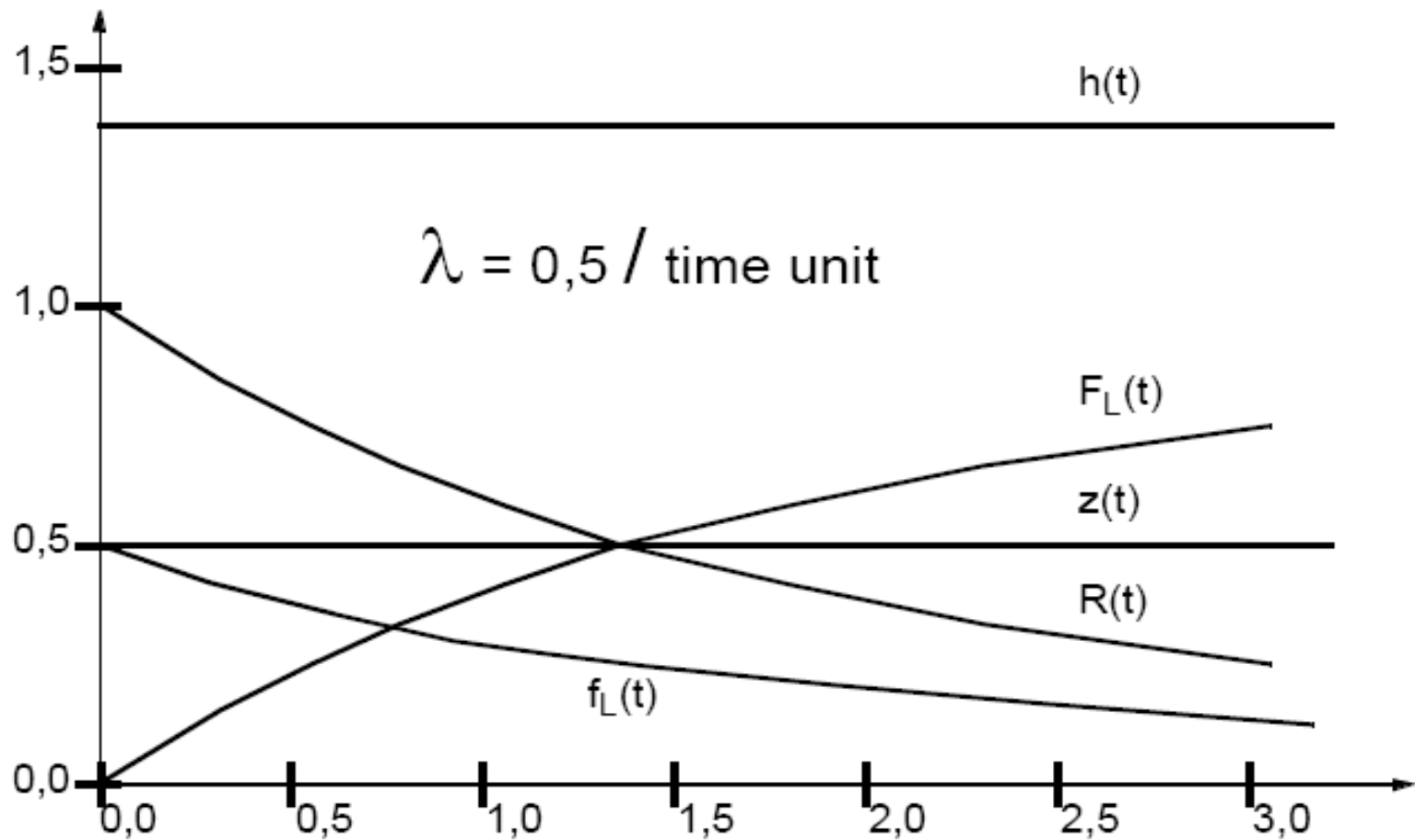
Failure prob.:  $F(t) = \int_0^t (\lambda \cdot e^{-(\lambda \cdot x)}) dx = -\left(e^{-(\lambda \cdot x)}\right) \Big|_0^t = 1 - e^{-(\lambda \cdot t)}$

Reliability:  $R(t) = e^{-(\lambda \cdot t)}$

Mean time to f.:  $E(L) = \int_0^{\infty} (e^{-(\lambda \cdot t)}) dx = -\left(\frac{1}{\lambda} \cdot e^{-(\lambda \cdot t)}\right) \Big|_0^{\infty} = \frac{1}{\lambda}$

Failure rate:  $z(t) = \frac{f_L(t)}{R(t)} = \lambda \quad \text{constant}$

## Illustration of the Exponentially Distributed Time to Failure



## Stationary availability

Only for repairable systems the **stationary availability** (steady-state availability)

$V$  is defined by

$$V = \frac{E_L}{E_L + E_R} = \frac{MTTF}{MTTF + MTTR}$$

The availability  $V$  denotes the probability, that a system is properly functioning at any point in time. The general (time dependent) availability  $V(t)$  can only be calculated after the introduction of a **state model**.

Mean time to failure (MTTF)  $E_L$  or  $E(L)$

Mean time to repair (MTTR)  $E_R$  or  $E(B)$

Assumption: **Exponential distribution**

$$V = \frac{1/\lambda}{1/\lambda + 1/\mu} = \frac{1/\lambda}{\frac{\mu + \lambda}{\lambda \cdot \mu}} = \frac{\mu}{\lambda + \mu}$$

$$E_L = 1/\lambda$$

$$E_R = 1/\mu$$

Where  $\lambda$  - failure rate,  
 $\mu$  - repair rate

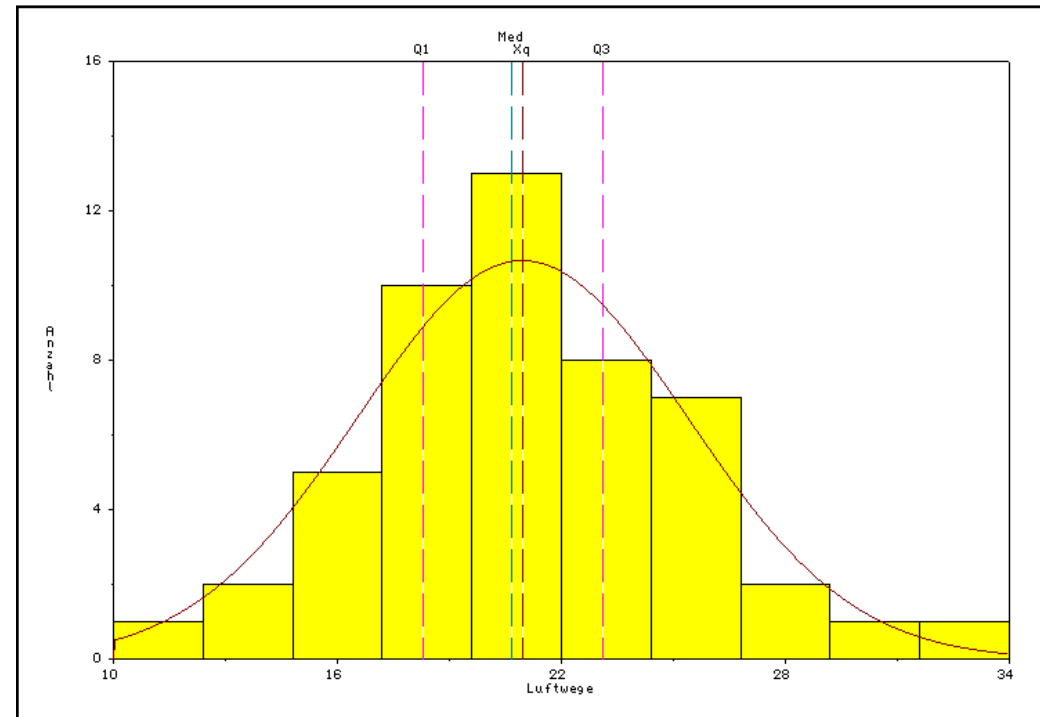


## Statistical data and (statistical) distribution function

A **histogram** is the graphical version of a table that shows what proportion of cases (relative occurrence) fall into each of specified intervals. A generalization of the histogram construct a very smooth **probability density function** from the supplied data.

### Questions the Histogram Answers

- What is the most common value?
- What distribution (center, variation and shape) does the data have?



To check with Kolmogorov's or  $\chi^2$  criteria.

## Application examples of distributions

| Distribution       | Field of Application   |
|--------------------|--|
| Exponential        | for constant failure rate  |
| Weibull            | $\beta > 1$ for monotone increasing rates<br>$\beta < 1$ for monotone decreasing rates |
| Normal             | In case of statistically independent<br>random variables                               |
| Logarithmic Normal | for time to repair   |
| Uniform            | for wear-out failures  |
| Binomial           | for n-out-of-m systems   |
| Poisson            | for statistical reliability experiment   |

## Exercise example:

For a larger number of simultaneously implemented identical devices it was discovered after one year that 5% of the devices failed, and were not repaired.

1. What is the mean lifetime  $E$  of the devices, if an **exponential distribution** with parameter  $\lambda$  is assumed?

2. What is the mean lifetime  $E$  of the devices, if an **uniform distribution** with the parameters  $a$  and  $b$  is assumed and  $a = 0$ ?

What assumption leads to more optimistic reliability forecast?

## Solution:

### 1. Exponential distribution

$$R(t) = e^{-\lambda \cdot t}$$

t=1 year, F(t)= 0.05 (5%), than R(t)=0.95

$$R(t = 1) = e^{-\lambda \cdot 1 \text{ year}} = 0.95, \quad \lambda = \frac{-\ln 0.95}{1 \text{ year}} = 5.13 \cdot 10^{-2} / \text{year}$$

Mean lifetime  $E_{\text{exp}} = 1/\lambda = 19,5 \text{ years}$

## Solution:

### 2. Uniform distribution

$$R(t) = \frac{b-t}{b-a}$$

$t=1$  year,  $F(t)=0.05$  (5%), then  $R(t)=0.95$

$$R(t) = \frac{b-t}{b-a} = \frac{b-1}{b-0} = 0.95, \quad b-1 \text{ year} = 0.95b \Rightarrow b = 20 \text{ years}$$

Mean lifetime  $E_{\text{uni}} = (a+b)/2 = 10$  years

$$E_{\text{exp}} \neq E_{\text{uni}}$$

## Interaction of different distributed failure effects (I)

Assumptions:

- Failures are independent,
- Failure effects interact **one after another**.

In general: 
$$R(t) = \prod_{i=1}^N R_i(t)$$

By 2 failure effects:  $R(t) = R_1(t) \cdot R_2(t)$ ,  $F(t) = 1 - R_1(t) \cdot R_2(t)$ ,

$$f(t) = -\frac{d(R_1(t) \cdot R_2(t))}{dt} = -\dot{R}_1(t) \cdot R_2(t) - R_1(t) \cdot \dot{R}_2(t), \quad E = \int_0^{\infty} R_1(t) \cdot R_2(t) dt,$$

$$z(t) = \frac{-\dot{R}_1(t) \cdot R_2(t) - R_1(t) \cdot \dot{R}_2(t)}{R_1(t) \cdot R_2(t)} = \frac{-\dot{R}_1(t)}{R_1(t)} + \frac{-\dot{R}_2(t)}{R_2(t)} = z_1(t) + z_2(t)$$

Failure rates are added.

## Interaction of different distributed failure effects (II)

Assumptions:

- Failures are independent,
- 2 failure effects, both **exponential distributed** with  $\lambda_1$  and  $\lambda_2$ .

$$R(t) = e^{-\lambda_1 t} \cdot e^{-\lambda_2 t} = e^{-(\lambda_1 + \lambda_2)t}$$

→ also exponential distributed with  $\lambda = \lambda_1 + \lambda_2$

$$E = \frac{1}{\lambda_1 + \lambda_2}$$

## Interaction of different distributed failure effects (III)

Assumptions:

- Failures are independent,
- 2 failure effects, both **weibull distributed** with  $\alpha_1, \beta_1$  and  $\alpha_2, \beta_2$ .

$$R(t) = e^{-\frac{1}{\alpha_1}t^{\beta_1}} \cdot e^{-\frac{1}{\alpha_2}t^{\beta_2}} = e^{-\left(\frac{1}{\alpha_1}t^{\beta_1} + \frac{1}{\alpha_2}t^{\beta_2}\right)}$$

→ **only** by  $\beta_1 = \beta_2$  weibull distributed with  $1/\alpha = 1/\alpha_1 + 1/\alpha_2$

$$z(t) = \frac{\beta_1}{\alpha_1} t^{\beta_1-1} + \frac{\beta_2}{\alpha_2} t^{\beta_2-1}, \quad f(t) = z(t) \cdot R(t)$$

$$E = ?$$